

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

SN54259, SN54LS259B, SN74259, SN74LS259B 8-BIT ADDRESSABLE LATCHES

DECEMBER 1983 — REVISED MARCH 1988

- 8-Bit Parallel-Out Storage Register Performs Serial-to-Parallel Conversion with Storage
- Asynchronous Parallel Clear
- Active High Decoder
- Enable/Disable Input Simplified Expansion
- Expandable for N-Bit Applications
- Four Distinct Functional Modes
- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

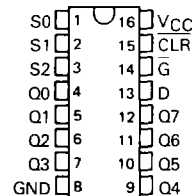
description

These 8-bit addressable latches are designed for general purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and active-high decoders or demultiplexers. They are multifunctional devices capable of storing single-line data in eight addressable latches, and being a 1-of-8 decoder or demultiplexer with active-high outputs.

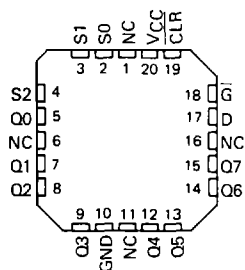
Four distinct modes of operation are selectable by controlling the clear (CLR) and enable (G) inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in terminal is written into the addressed latch. The addressed latch will follow the data input with all unaddressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latches, enable G should be held high (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode, the addressed output will follow the level of the D input with all other outputs low. In the clear mode, all outputs are low and unaffected by the address and data inputs.

The SN54259 and SN54LS259B are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74259 and SN74LS259B are characterized for operation from 0°C to 70°C.

SN54259, SN54LS259B . . . J OR W PACKAGE
SN74259 . . . N PACKAGE
SN74LS259B . . . D OR N PACKAGE
(TOP VIEW)

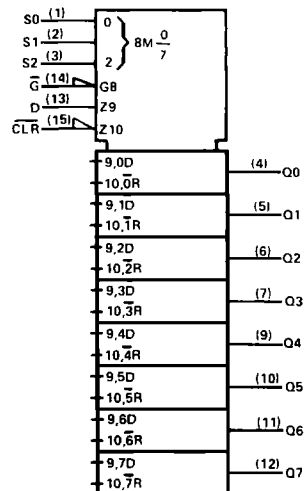


SN54LS259B . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12

Pin numbers shown are for D, J, N, and W packages.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TEXAS
INSTRUMENTS

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TTL Devices

SN54259, SN54LS259B, SN74259, SN74LS259B 8-BIT ADDRESSABLE LATCHES

FUNCTION TABLE

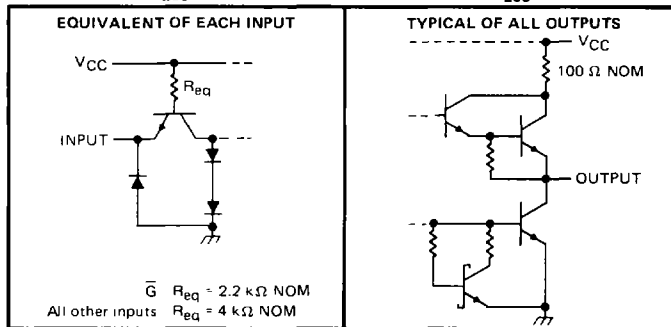
INPUTS		OUTPUT OF ADDRESSED LATCH	EACH OTHER OUTPUT	FUNCTION
CLR	\bar{G}			
H	L	D	Q_{i0}	Addressable Latch
H	H	Q_{i0}	Q_{i0}	Memory
L	L	D	L	8-Line Demultiplexer
L	H	L	L	Clear

H = high level, L = low level
 D = the level at the data input
 Q_{i0} = the level of Q_i ($i = 0, 1, \dots, 7$ as appropriate) before the indicated steady-state input conditions were established.

LATCH SELECTION TABLE

SELECT INPUTS			LATCH ADDRESSED
S2	S1	S0	
L	L	L	0
L	L	H	1
L	H	L	2
L	H	H	3
H	L	L	4
H	L	H	5
H	H	L	6
H	H	H	7

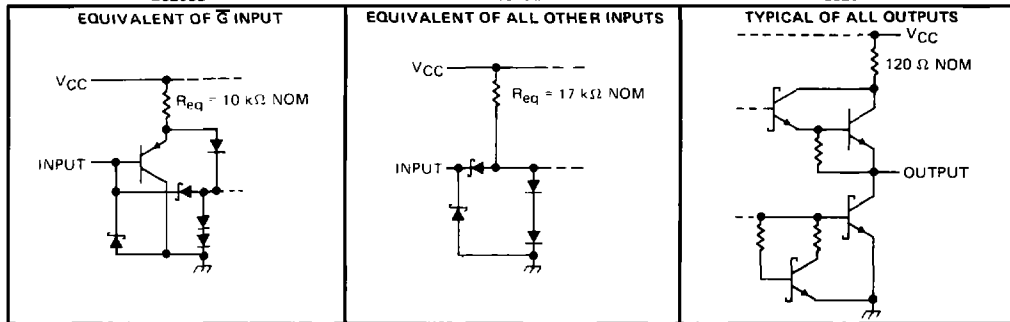
schematic of inputs and outputs '259



LS259B

'LS259B

'LS259B



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage (see Note 1)	7 V
Input voltage: SN54259, SN74259	5.5 V
SN54LS259B, SN74LS259B	7 V
Operating free-air temperature range: SN54259, SN54LS259B	-55°C to 125°C
SN74259, SN74LS259B	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

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TTL Devices

SN54259, SN74259
8-BIT ADDRESSABLE LATCHES

recommended operating conditions

	SN54259			SN74259			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}			-800			-800	μ A
Low-level output current, I_{OL}			16			16	mA
Width of clear or enable pulse, t_w	15			15			ns
Setup time, t_{su}	Data	15 \uparrow		15 \uparrow			ns
	Address	5 \uparrow		5 \uparrow			
Hold time, t_h	Data	0 \uparrow		0 \uparrow			ns
	Address	20 \uparrow		20 \uparrow			
Operating free-air temperature, T_A	-55	125		0	70		$^{\circ}$ C

\uparrow The arrow indicates that the rising edge of the enable pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS \dagger	SN54259			SN74259			UNIT
			MIN	TYP \ddagger	MAX	MIN	TYP \ddagger	MAX	
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = 12 \text{ mA}$			-1.5			-1.5	V
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -800 \mu\text{A}$	2.4	3.4		2.4	3.4		V
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$	0.2	0.4		0.2	0.4		V
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	High-level input current	\bar{G}			80			80	μ A
		Other inputs	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$		40		40		
I_{IL}	Low-level input current	\bar{G}			-3.2			-3.2	mA
		Other inputs	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$		-1.6		-1.6		
I_{OS}	Short-circuit output current \S	$V_{CC} = \text{MAX}$	-18	-57		-18	-57		mA
I_{CC}	Supply current	$V_{CC} = \text{MAX},$ See Note 2	60	90		60	90		mA

\dagger For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

\ddagger All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$.

\S Not more than one output should be shorted at a time.

NOTE 2 I_{CC} is measured with the inputs grounded and the outputs open.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PHL}	\bar{CLR}	Any Q	$C_L = 15 \text{ pF}, R_L = 400 \Omega,$ See Note 3		16	25	ns
t_{PLH}	Data	Any Q			14	24	
t_{PHL}	Address	Any Q			11	20	ns
t_{PLH}					15	28	
t_{PHL}	\bar{G}	Any Q			17	28	ns
t_{PLH}					12	20	
t_{PHL}					11	20	ns

t_{PLH} = propagation delay time, low-to-high-level output

t_{PHL} = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1

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TTL Devices



SN54LS259B, SN74LS259B 8-BIT ADDRESSABLE LATCHES

recommended operating conditions

	SN54LS259B			SN74LS259B			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			-0.4			-0.4	mA
I _{OL} Low-level output current			4			8	mA
t _w Pulse duration	\bar{G} low		17			17	ns
	CLR low		10			10	
t _{su} Set up time	Data before \bar{G} ↑		20			20	ns
	Address before \bar{G} ↑		17			17	
	Address before \bar{G} ↓		0			0	
t _h Hold time	Data after \bar{G} ↑		0			0	ns
	Address after \bar{G} ↑		0			0	
T _A Operating free-air temperature			-55			125	°C

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TTL Devices

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54LS259B		SN74LS259B		UNIT		
		MIN	TYP	MAX	MIN		TYP	MAX
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.5		-1.5	V	
V _{OH}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX, I _{OH} = -0.4 mA	2.5	3.4		2.7	3.4	V	
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX, I _{OL} = 4 mA		0.25	0.4		0.25	0.4	V
	I _{OL} = 8 mA					0.35	0.5	
I _I	V _{CC} = MAX, V _I = 7 V			0.1		0.1	mA	
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			20		20	μA	
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-0.4		-0.4	mA	
I _{OS‡}	V _{CC} = MAX	-20		-100	-20		-100	mA
I _{CC}	V _{CC} = MAX, See Note 2		27	36		22	36	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C

§ Not more than one output should be shorted at a time, and duration short-circuit should not exceed one second.

NOTE 2 I_{CC} is measured with the inputs grounded and the outputs open.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PHL}	CLR	Any Q	C _L = 15 pF, R _L = 2 kΩ, See Note 3		12	18	ns
t _{PLH}	Data	Any Q			19	30	
t _{PHL}	Address	Any Q			13	20	ns
t _{PLH}					17	27	
t _{PHL}	\bar{G}	Any Q			14	20	ns
t _{PLH}					15	24	
t _{PHL}					15	24	

t_{PLH} = propagation delay time, low-to-high-level output

t_{PHL} = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.